Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/500,131	MADTER ET AL.	
Examiner	Art Unit	
James K. Trujillo	2116	

	SEAR	CHED	4 42
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	9/20/2006	JKT
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